

**Notice of References Cited**

Application/Control No.

09/650,173

Applicant(s)/Patent Under

Reexamination

LEE, NICHOLAS J.

Examiner

Michael N. Opsasnick

Art Unit

2655

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,311,182	10-2001	Colbath et al.	707/6
	B	US-5,917,889	06-1999	Brotman et al.	379/88.01
	C	US-6,434,524	08-2002	Weber, Dean	704/257
	D	US-6,148,105	11-2000	Wakisaka et al.	382/190
	E	US-5,917,944	06-1999	Wakisaka et al.	382/190
	F	US-6,014,624	01-2000	Raman, Vijay R.	704/243
	G	US-6,324,513	11-2001	Nagai et al.	704/275
	H	US-6,308,157	10-2001	Vanbuskirk et al.	704/275
	I	US-6,334,103	12-2001	Surace et al.	704/257
	J	US-6,073,100	06-2000	Goodridge, Jr., Alan G	704/258
	K	US-6,144,938	11-2000	Surace et al.	704/257
	L	US-6,061,654	05-2000	Brown et al.	704/275
	M	US-6,137,863	10-2000	Brown et al.	379/88.01

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.